OIML-CS

Report on the OIML Certification System (OIML-CS) Seminar

15 June 2017 Shanghai, P.R. China

PAUL DIXON, BIML

n international seminar on the OIML Certification System (OIML-CS), jointly organized by AQSIQ and the OIML, was held on 15 June 2017 in Shanghai, P.R. China. It was attended by over 400 participants, with attendees coming from more than 20 economies.

The seminar was organized as an OIML Pilot Training Center under the theme of "Promoting Global Harmonization for Measuring Instruments", and was primarily aimed at providing information on the OIML-CS to interested stakeholders including potential OIML Issuing Authorities, Utilizers, Associates and manufacturers. More than half of the participants at the seminar were representatives from manufacturers of measuring instruments. In addition, high level repres-

entatives from AQSIQ, including Pu Changcheng and Wu Qinghai, and the Shanghai People's Government were in attendance.

The seminar began wih opening addresses from Wu Qinghai, Xu Kunlin (Shanghai People's Government) and Roman Schwartz (CIML First Vice-President and prMC Chairperson). The seminar, which was chaired by Xie Jun (AQSIQ) in the morning and Roman Schwartz in the afternoon, was then organized into the following sessions:

- Introduction to the OIML;
- Introduction and general information on the OIML-CS;
- Stakeholder perspectives and experience sharing;
- Preparing for the new OIML-CS; and
- What will happen after implementation?

The first session included a presentation from Roman Schwartz on the role of the OIML and a presentation from Luis Mussio (BIML) on the role of OIML Recommendations in OIML certificate systems. Xiao Jianhua (IAF President) also gave a presentation on cooperation between the OIML and the IAF. His participation in the seminar demonstrated the importance of the relationship that the OIML has with the international accreditation community, and IAF support in developing a Joint Assessment Procedure for the assessment of OIML Issuing Authorities under the OIML-CS.

The second session was devoted to introducing the new OIML-CS and included a presentation from Roman



Delegates attending the OIML-CS seminar









Wu Qinghai

Roman Schwartz

Paul Dixon

Luis Mussio

Schwartz on the background for the need to develop the OIML-CS to replace the existing OIML Basic Certificate System and the OIML Mutual Acceptance Arrangement (MAA). Paul Dixon (BIML, OIML-CS Executive Secretary) gave a detailed introduction to the OIML-CS, including information on the management and document structures and the requirements for participation under Scheme A and Scheme B, and the session was concluded by a presentation from Peter Ulbig (PTB, Germany) on the expected benefits that the new OIML-CS will bring to the stakeholders.

Session 3 provided an opportunity for stakeholders in the OIML-CS to provide their perspectives and experiences of the existing OIML certificate systems and the benefits that they envisage from the introduction of the new OIML-CS. Roland Nater (CECIP) gave an industry view on the introduction of the new OIML-CS, and he was followed by Cock Oosterman (NMi, Netherlands), Darrell Flocken (NCWM, United States) and Bill Loizides (NMI Australia) who provided the perspectives of OIML Issuing Authorities and Utilizers. Fang Xiang from National Institute of Metrology (NIM) explained how the OIML-CS will be implemented in P.R. China.

Information and an explanation of the steps that stakeholders will need to take to participate in the new OIML-CS was the focus of the fourth session. Paul Dixon and Roman Schwartz gave an overview of the timeline for the implementation of the OIML-CS, including information on the instrument categories that will be included in the OIML-CS, in which Scheme (A or B) and the transition from Scheme B to Scheme A, along with information on the work of the provisional Management Committee (prMC). Harry Stolz (PTB, Germany) and Cock Oosterman (on behalf of Stefan Kral, SLM, Slovakia) provided important information on the steps that their organizations are taking to become OIML Issuing Authorities in the OIML-CS.

Seminar on the OIML-CS

Promoting Global Harmonization for Measuring Instruments

Agenda

Registration	-
Welcome address from the Shanghai Government	Shanghai Govt.
Opening remarks from the OIML	Roman Schwartz (prMC Chair)
Opening remarks from AQSIQ	Wu Qinghai (AQSIQ, P.R. China
Session 1: Introduction to the OIML	
Role of the OIML	Roman Schwartz (prMC Chair)
OIML Recommendations and their role in OIML	Luis Mussio (BIML)
Certificate Systems	
IAF and it's cooperation with the OIML	Xiao Jianhua (IAF President)
Session 2: Introduction and general information on the	
OIML-CS	
General information about the new OIML-CS	Roman Schwartz (prMC Chair)
 Introduction to the new OIML-CS 	Paul Dixon (BIML)
Expected benefits of the new OIML-CS	Peter Ulbig (PTB, Germany)
Session 3: Stakeholder perspectives and experience	
sharing	
Industry	Roland Nater (CECIP)
Issuing Authorities and Utilizers	Cock Oosterman (NMi, NL)
	Darrell Flocken (NCWM, US)
	Bill Loizidies (NMI Australia)
Implementation of the OIML-CS in China	Fang Xiang (NIM, P. R. China)
Session 4: Preparing for the new OIML-CS	
What needs to be done to implement the OIML-CS?	0 10: (004)
Timeline for implementation	Paul Dixon (BIML)
Activities of the prMC Activities of the prMC	Roman Schwartz (prMC Chair)
 Information on the OIML-CS website 	Paul Dixon (BIML)
What do people have to do to participate?	
 Steps to take to become an Issuing Authority, 	Harry Stolz (PTB, Germany)
Utilizer or Associate (case studies)	Stefan Kral (SLM, Slovakia)
Session 5: What will happen after implementation?	
Validity of old certificates	Luis Mussio (BIML)
Next MC meeting	Roman Schwartz (prMC Chair
How to become a member of the MC	Paul Dixon (BIML)
How to become a legal metrology expert and/or a lead	Peter Ulbig (PTB, Germany)
assessor for ISO/IEC 17025 and ISO/IEC 17065	
Test Laboratories Forum	Harry Stolz (PTB, Germany)
Session 6: Panel Discussion	

The final session was devoted to aspects of the OIML-CS following its implementation. This included presentations from Luis Mussio on the validity of existing OIML Basic and MAA certificates and Paul Dixon on how to participate in the Management Committee that will be established to manage the operation of the OIML-CS. Peter Ulbig provided detailed information on how to become a legal metrology expert or lead assessor for participating in the accreditation and peer assessments of participants in the OIML-CS, and Harry Stolz introduced the Test Laboratories Forum and the important role that it will play in supporting the development of harmonized test procedures and of OIML Recommendations.

The seminar was concluded with a panel discussion which aimed to provide the participants at the seminar with an opportunity to ask questions about the new OIML-CS and its implementation. The panel comprised Xie Jun, Cai Changqing (NIM), Roman Schwartz, Paul Dixon, Charles Ehrlich (NIST, United States), Bill Loizides and Karlheinz Banholzer (CECIP). Over the course of 90 minutes they responded to a range of questions from the participants, with the number and quality of the questions demonstrating a keen interest from those present in the OIML-CS.

All of the presentations from the seminar have been made available on the OIML website and can be downloaded from https://www.oiml.org/en/events/oiml-seminars

In conclusion, this was an important event which has supported the promotion and awareness-raising of the new OIML-CS. AQSIQ and the OIML are very grateful to the experts that participated in the seminar and who made it such an interesting and informative event for stakeholders. In conjunction with the second prMC meeting, and the final CPRs meeting under the OIML MAA (see report on page 37), the events that were so well organized and hosted by AQSIQ were very successful and will go a long way to ensuring that the OIML-CS will come into operation on 1 January 2018.

Other promotion and awareness-raising activities will be held in the future, including opportunities to participate in meetings and events organized by Regional Legal Metrology Organizations (RLMOs). A seminar on the OIML-CS will be held in Cartagena de Indias, Colombia in conjunction with the CIML meeting in October 2017. Further information is available at: http://cartagena.oiml.org/seminar.html



Delegates attending the OIML-CS seminar